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Information technology — Security techniques — Testing methods for the mitigation of noninvasive attack classes against cryptographic modules

Techonologie de l'information — Techniques de sécurité — Methodes de test pour la protection contre les attaques non intrusives des modules cryptographiques.

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Foreword

ISO (the International Organization for Standardization) and IEC (the International Electrotechnical Commission) form the specialized system for worldwide standardization. National bodies that are members of ISO or IEC participate in the development of International Standards through technical committees established by the respective organization to deal with particular fields of technical activity. ISO and IEC technical committees collaborate in fields of mutual interest. Other international organizations, governmental and non-governmental, in liaison with ISO and IEC, also take part in the work.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of document should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives or www.iec.ch/members-experts/refdocs).

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For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT) see www.iso.org/iso/fore-word.html. In the IEC, see <a href="www.iec.ch/understanding-stand-december-www.iec.ch/understanding-stand-december-www.iec.ch/understanding-stand-december-www.iec.ch/understanding-stand-december-www.iec.ch/understanding-standards.

This document was prepared by Technical Committee ISO/IEC JTC-1, *Information technology*, Subcommittee SC 27, *Information security, cybersecurity and privacy protection*.

This second edition cancels and replaces the first edition (ISO/IEC 17825:2016), which has been technically revised.

The main changes are as follows:

- test methods have been updated as per research trends;
- an introduction has been added which states the expectations in terms of security level of this document;
- requirements have been numbered. This help ensuring to ensure, their traceability.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html and www.iec.ch/national-committees.

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Introduction

Testing requires defined constants, which are derived from an axiomatic analysis of the security problem. The security assurance levels are bound to the testing and remaining risks. The testing approach can be characterized as follows:

a) Testing soundness

- Formal formal description of empirical closed-box testing provides the soundness, in the context df
 the attack, because the testing adheres to an accepted methodology.
- 2) The application of the methodology does not ensure that all possible attacks are covered. Testing allows for weakness detection in a system; hence, it increases the confidence in a system's ability to withstand a set of simulated attacks. The implemented formalism allows to detect weaknesses, and the outcome is a reasonable level attested by tests.
- 3) The level of assurance that can be reached with the methodology in this document is a ""controlled" level of ""reasonable" confidence level, which is the level low to medium. Level high is not reachable due to the closed-box approach. The meaning of ""reasonable" is determined by the customer's risk threshold. The tester is defining the level of reasonability, in accordance with a security level target.
- 4) Testing is guided by a strategy, which allows for transparency in the methodology and outcomes.
- The methodology is device-class specific. The pass/fail criteria should take into account the class of devices under test. For example, the criteria for devices with a deterministic behaviour (i.e. bare metal), and for devices with a complex software stack should be different.
- 6) Security testing is an ""estimation" when based upon noisy measurements, or when the tester does not have full control of the implementation under test (IUT).
- b) Repeatability (as per ISO/IEC 17025:2017[68], 7.2.2.4)

Repeatability means similar results from the same (i.e., repeated) methodology, while reproducibility means similar results from similar methodology. Security evaluation is an estimation based on noisy measurements, on IUT whose behaviour is probably not in full control of the tester. In this document, there is a prerequisite that the IUT is closed-box, which can behave in a non-deterministic manner (at least, its internals – owing to some intentional randomization used as a protection). Furthermore, the test can only be carried out based on external observations and findings. As a result, the objective is to document a formal and transparent process of testing, where independent tests can be reproduced with similar expected results (as much as possible, within reasonable bounds). The methodologies are similar (e.g., executed by two testers) in that they yield similar outcome.

c) Cost of testing

- The objective is to devote the right amount of effort for the testing of a given assurance level. Cost
 effectiveness of the testing has a direct implication on assuring a certain level of security. Cost of testing
 includes, but is not limited to:
 - Level of expertise and experience: Consequence/implication of using an already formalized process (agnostic in the IUT). The testers require skills and competencies.

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- ii) Time: Elapsed time for data acquisition, even though the procedure is automated.
- iii) Equipment: The cost impact of equipment is covered in ISO/IEC 20085-1:2019[69] (requirements) and ISO/IEC 20085-2:2020[79] (calibration).
- 2) This document aims to keep cost moderate. A threshold is reached in the assurance level up to a certain number of traces captured. The level of assurance does not increase significantly more beyond the threshold. The prescribed methodology cannot exceed a certain level of assurance by its design.

As a consequence of trade-offs made during the definition of this document and The following statements apply as an artefactartifact of the methodology used:

- d)-_Closed-box testing limits this methodology to exclusively test for leakage that does not account for specific features of a given algorithm's implementation (e.g. implementation specificities, such as parallel execution of unrelated cryptographic operations, or countermeasures, such as random masking, implementation of field arithmetic in elliptic curve cryptography).
- e)-_Testing only considers leakage during tested cryptographic operations using keys. By design the process does not look for other potential sources of leakage (e.g. emissions during transit of keys over internal bus).
- f)- Results are dependent on the data_sets and quality of equipment used during acquisition. Attackers with larger resources can still be able to exploit attack paths tested by this methodology, even if they had passed the test based on increased resources and effort.
- g)- More sophisticated attacks can be applied and succeed. More sophisticated attacks refers to attacks other than conventional ones, for example the attacks that are particular to asymmetric ciphers (see 9.2).
- h)- Each specific application/cryptographic module API instance also requires a delta evaluation on top of the generic tests in this document. Such areas of assessment should include application-specific non-parametric module usage threats, such as traffic analysis, manipulation of logical order or scope of external operations.

In this document, requirements are numbered. By convention, the requirements are labelled as [CC.NN], where CC represents the clause number (e.g. 06 means Clause 6), and NN represents the requirement position within the Clause (e.g. the first requirement of Claude 6 is referred to as [06.01]). The purpose of labelled requirements is to ease the generation of documents showing compliance with this document, and their traceability for testers.

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Information technology — Security techniques — Testing methods for the mitigation of non-invasive attack classes against cryptographic modules

1 Scope

This document specifies the non-invasive attack mitigation test metrics for determining conformance to the requirements specified in ISO/IEC 19790:2012 for security levels 3 and 4. The test metrics are associated with the security functions addressed in ISO/IEC 19790:2012. Testing is conducted at the defined boundary of the cryptographic module and Imputs/Outputsthe inputs/Outputs available at its defined boundary.

This document is intended to be used in conjunction with ISO/IEC 24759:2017 to demonstrate conformance to ISO/IEC 19790:2012.

NOTE __ISO/IEC 24759:2017, specifies the test methods used by testing laboratories to assess whether the cryptd-graphic module conforms to the requirements specified in ISO/IEC 19790:2012 and the test metrics specified in this document for each of the associated security functions specifiedaddressed in ISO/IEC 19790:2012.

The test approach employed in this document is an efficient "push-button" approach, i.e. the tests are technically sound, repeatable and have moderate costs.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO/IEC~19790:2012, Information~technology --- Security~techniques --- Security~requirements~for~cryptographic~modules

ISO/IEC 24759:2017, Information technology — Security techniques — Test requirements for cryptographic modules

3 Terms and definitions

For the purposes of this document, the terms and definitions given in ISO/IEC 19790 and the following apply.

ISO and IEC maintain terminology databases for use in standardization at the following addresses;

- ISO Online browsing platform: available at https://www.iso.org/obp
- IEC Electropedia: available at https://www.electropedia.org/

3.1

advanced side-channel analysis

ASCA

advanced exploitation of the instantaneous side-channels emitted by a cryptographic device that depends on the data it processes and on the operation it performs to retrieve secret parameters

3.2

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correlation power analysis

CPA

analysis where the correlation coefficient is used as the statistical method

33

critical security parameter class

CSP class

class into which a critical security parameter (3.3) is categorised

EXAMPLE Cryptographic keys, authentication data such as passwords, PINs, biometric authentication data.

3.4

$differential\ electromagnetic\ analysis$

DEMA

analysis of the variations of the electromagnetic field emanated from a cryptographic module, using statistical methods on a large number of measured electromagnetic emanations values for determining whether the assumption of the divided subsets of a secret parameter is correct, for the purpose of extracting information correlated to security function operation

3.5

differential power analysis

DPA

analysis of the variations of the electrical power consumption of a cryptographic module, for the purpose of extracting information correlated to cryptographic operation

3.6

electromagnetic analysis

EMA

analysis of the electromagnetic field emanated from a cryptographic module as the result of its logic circuit switching, for the purpose of extracting information correlated to security function operation and subsequently the values of secret parameters such as cryptographic keys

3.7

implementation under test

IUT

implementation which is tested based on non-invasive methods specified in this document

3.8

power analysis

DA

analysis of the electric power consumption of a cryptographic module, for the purpose of extracting information correlated to the security function operation and subsequently the values of secret parameters such as cryptographic keys

3.9

side-channel analysis

SCA

exploitation of the fact that the instantaneous side-channels emitted by a cryptographic device depends on the data it processes and on the operation it performs to retrieve secret parameters

3.10

2

side-channel collision attack

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powerful category of *side-channel analysis* (3.102) that usually combines leakage from distinct points in tim $\frac{1}{2}$, making them inherently bivariate

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3.11

simple electromagnetic analysis

SEMA

direct (primarily visual) analysis of patterns of instruction execution or logic circuit activities, obtained through monitoring the variations in the electromagnetic field emanated from a cryptographic module, for the purpose of revealing the features and implementations of cryptographic algorithms and subsequently the values of secret parameters

3.12

simple power analysis

SPA

direct (primarily visual) analysis of patterns of instruction execution (or execution of individual instructions), in relation to the electrical power consumption of a cryptographic module, for the purpose of extracting information correlated to a cryptographic operation

3.13

timing analysis

TA

analysis of the variations of the response or execution time of an operation in a security function, which can reveal knowledge of or about a security parameter such as a cryptographic key or PIN

4 Symbols and abbreviated terms

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ASCA	advanced side-channel analysis	
AES	advanced encryption standard	
CPA	correlation power analysis	
CSP	critical security parameter	
DEMA	differential electromagnetic analysis	

DES data encryption standard
DLC discrete logarithm cryptography
DPA differential power analysis
DSA digital signature algorithm
ECC elliptic curve cryptography

ECDSA elliptic curve digital signature algorithm

EM electromagnetic

EMA electromagnetic analysis

HMAC keyed-hashing message authentication code

IFC integer factorization cryptography

IUT implementation under test

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MAC message authentication code

PA power analysis
PC personal computer
PCB printed circuit board

PKCS public-key cryptography standards

RBG random bit generator
RNG random number generator
RSA Rivest Shamir Adleman
SCA side-channel analysis

SEMA simple electromagnetic analysis

SHA secure hash algorithm
SNR signal to noise ratio
SPA simple power analysis
USB universal serial bus

TA timing analysis

multiplication symbol

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5 Document organization

Clause 6 specifies the non-invasive attack methods that a cryptographic module shall mitigate against for conformance to ISO/IEC 19790:2012.

Clause 7 specifies the non-invasive attack test methods.

Clause 8 specifies the test methods for side-channel analysis of symmetric-key cryptosystems.

Clause 9 specifies the test methods for side-channel analysis of asymmetric-key cryptosystems.

This document shall be used together with $ISO/IEC\,24759:2017$ to demonstrate conformance to $ISO/IEC\,19790:2012$.

6 Non-invasive attack methods

This clause specifies the non-invasive attack methods that shall [06.01] be addressed to ensure conformance towith ISO/IEC 19790:2012.

The non-invasive attacks use side-channels (information gained from the physical implementation of a cryptosystem) emitted by the implementation under test (IUT), such as:

- the power consumption of the IUT,
- the electromagnetic emissions of the IUT,
- the computation time of the IUT.

4

The number of possible side-channels can increase in the future (e.g. photonic emissions $\{149\}_{7}$ 1 acoustic emanations).

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In order to be more formal in the 'taxonomy taxonomy of the attacks, a formalism allows the relationships to be highlighted between the different attacks and to have a systematic way to describe a new attack.

An attack is described in the following way:

KKK refers to the order of the attack (e.g. "20" for second order attack).

YYY refers to the statistical treatment used in the attack (e.g. "S" for Simplesimple, "C"_for Gorrelation, "MI"_for Mutual Information mutual information, "ML" for Maximum Likelihood maximum likelihood, "D" for Difference of Means means, "LR" for Linear Regression inear regression, etc.).

NOTE₋1 Other statistical treatments can be inserted like "dOC" which corresponds to a correlation treatment exploiting *d*th order moments (obtained for instance, by raising each targeted point in the traces to a power *d*, or by combining *d* points per trace before processing the correlation).

XXX refers to the kind of observed side channel: e.g. "PA" for Power Analysis power analysis, "EMA" for Electromagnetic Analysis electromagnetic analysis, "TA" for Timing Analysis iming analysis, etc.

ZZZ can refer to the profiled ("P") or unprofiled ("UP") characteristic of the attack. This is optional and the default value is "UP".

TTT refers to the direction of the attack (e.g. "V" for Vertical "H" for Horizontal horizontal "R" for Rectangle rectangle).

